

Title (en)

SAMPLE CARRIER FOR ELECTRON MICROSCOPY

Title (de)

PROBENTRÄGER FÜR DIE ELEKTRONENMIKROSKOPIE

Title (fr)

SUPPORT D'ÉCHANTILLON POUR LA MICROSCOPIE ÉLECTRONIQUE

Publication

**EP 3739615 A1 20201118 (EN)**

Application

**EP 19174531 A 20190514**

Priority

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Abstract (en)

The invention relates to a sample carrier (1) for electron microscopy, in particular a sample carrier for imaging or diffraction experiments, e.g. under cryogenic conditions, comprising a support for a sample, e.g. an EM grid (2), and a rim (3) having a thickness greater than that of the support (2) for a sample. The support (2) for a sample and/or the rim (3) were formed and/or machined by means of laser ablation and/or laser welding.

IPC 8 full level

**H01J 37/20** (2006.01); **H01J 37/26** (2006.01)

CPC (source: EP)

**H01J 37/20** (2013.01); **H01J 37/26** (2013.01); **H01J 2237/20** (2013.01); **H01J 2237/2001** (2013.01)

Citation (applicant)

- US 4250127 A 19810210 - KUNDRATH MICHAEL R [US], et al
- WO 2016008502 A1 20160121 - SCIENION AG [DE]
- EP 1489642 A1 20041222 - FEI CO [US]
- WO 2017220750 A1 20171228 - UNIV MAASTRICHT [NL]

Citation (search report)

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- [AD] US 4250127 A 19810210 - KUNDRATH MICHAEL R [US], et al
- [AD] WO 2016008502 A1 20160121 - SCIENION AG [DE]
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Cited by

EP3786608A1; US11101104B2; EP4038655A4

Designated contracting state (EPC)

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